

FIG. 1

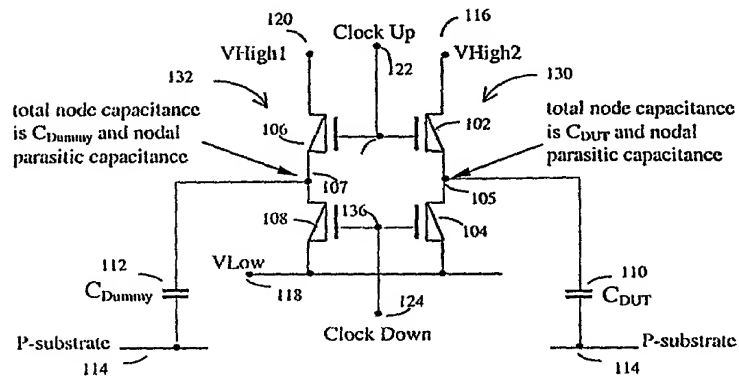


FIG. 2

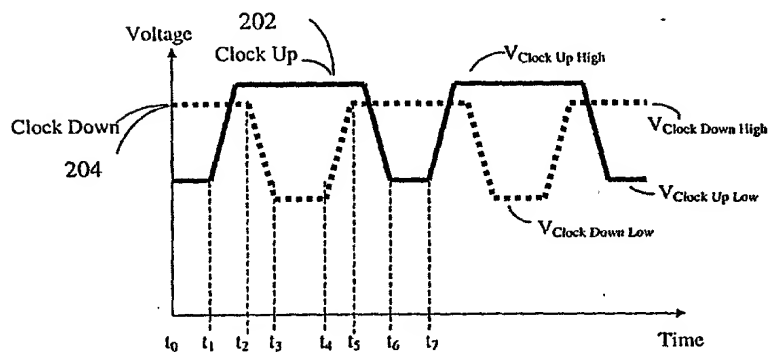


FIG.3

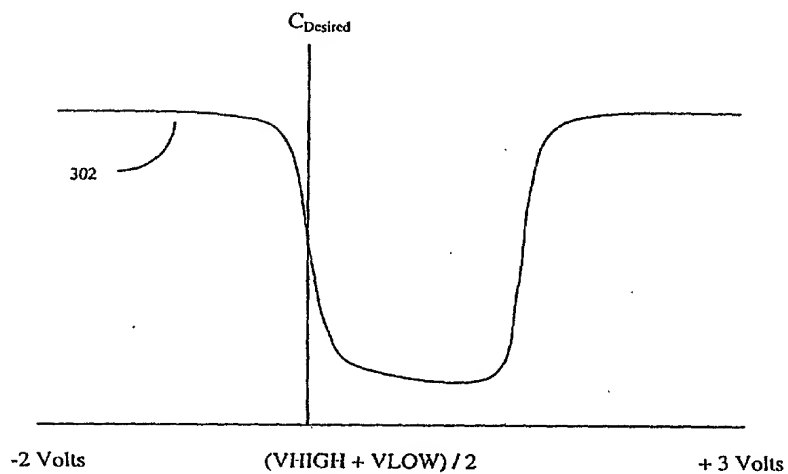


FIG. 4

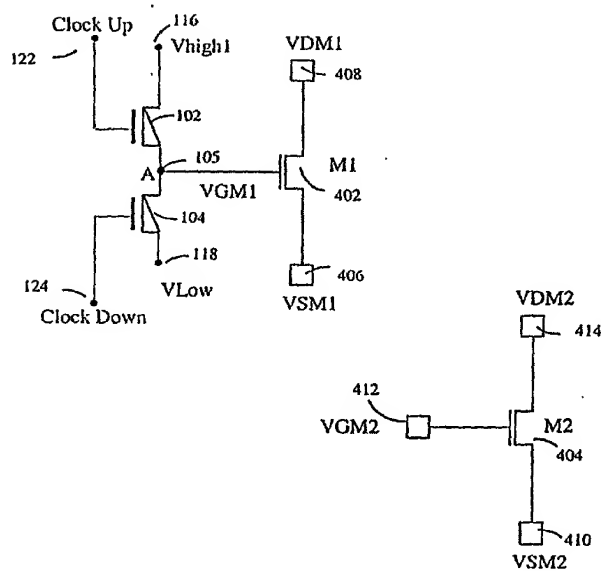
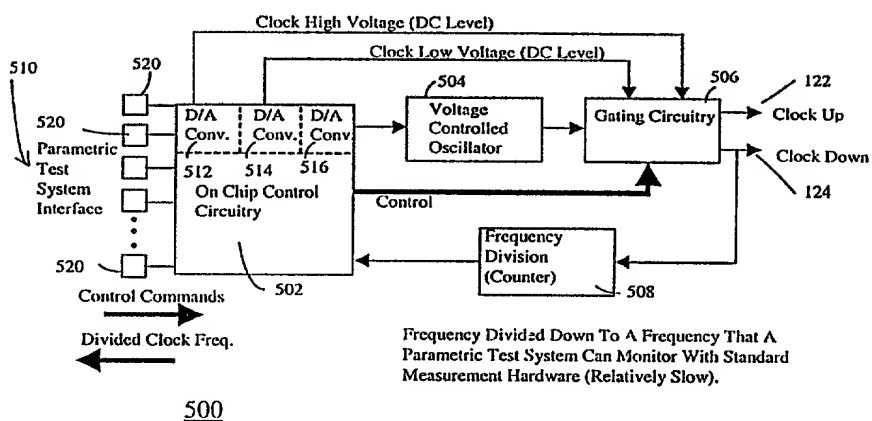


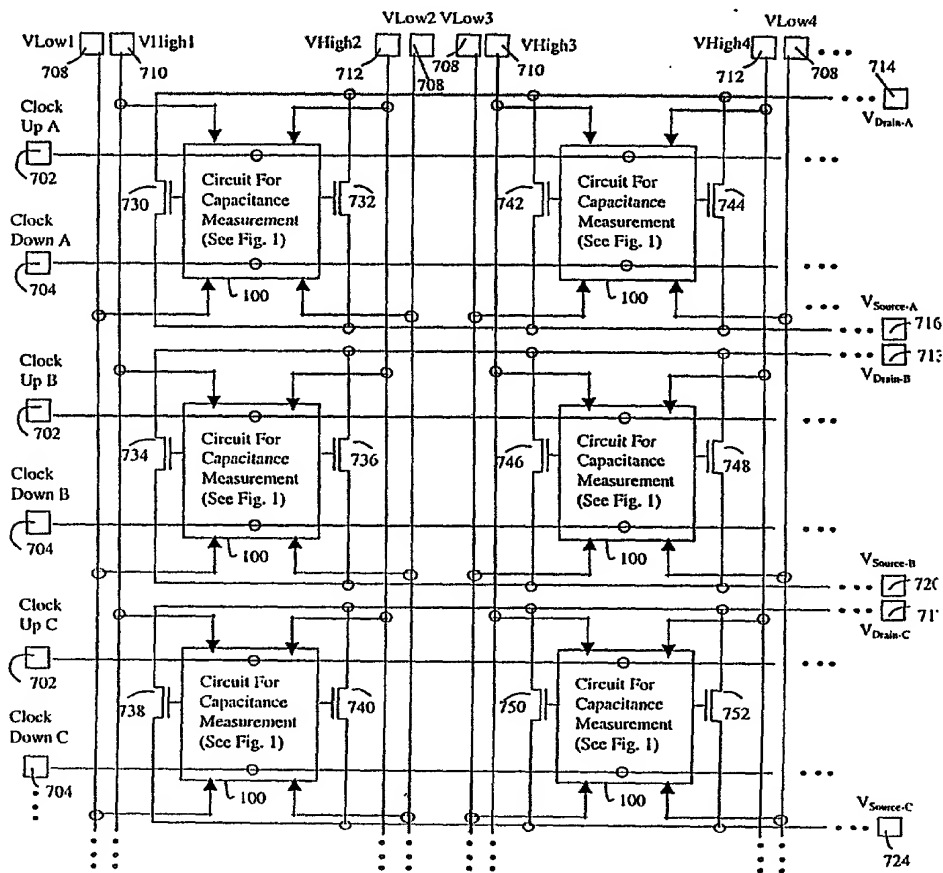
FIG. 5





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FIG. 7



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FIG. 8

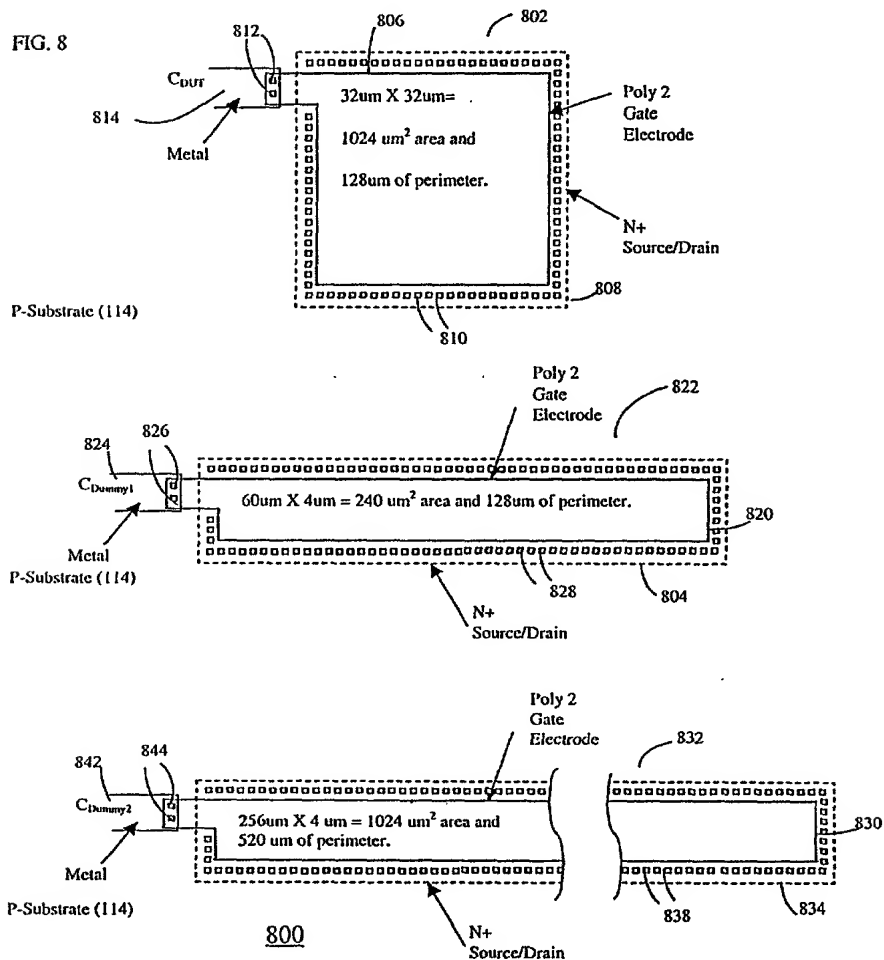
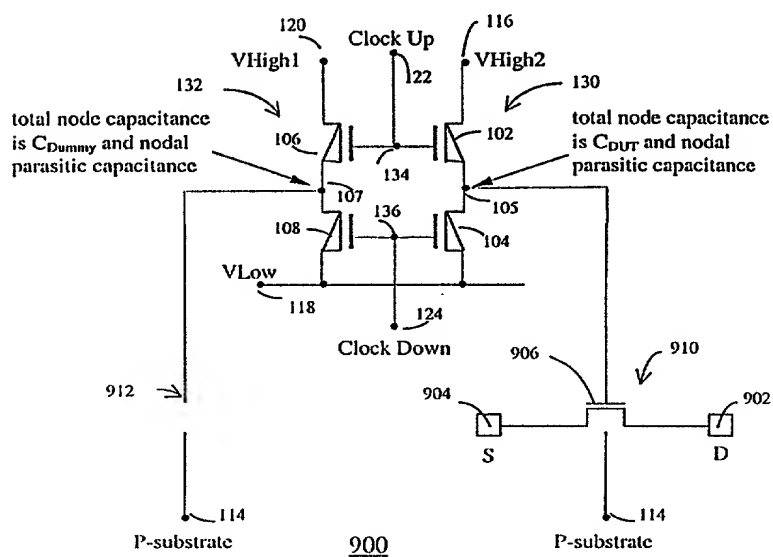




FIG. 9



[illegible]

FIG. 11

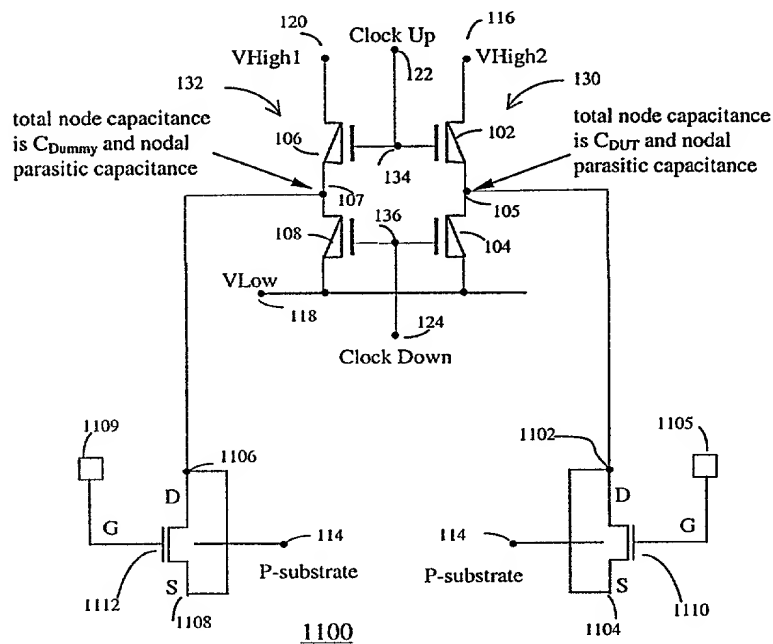
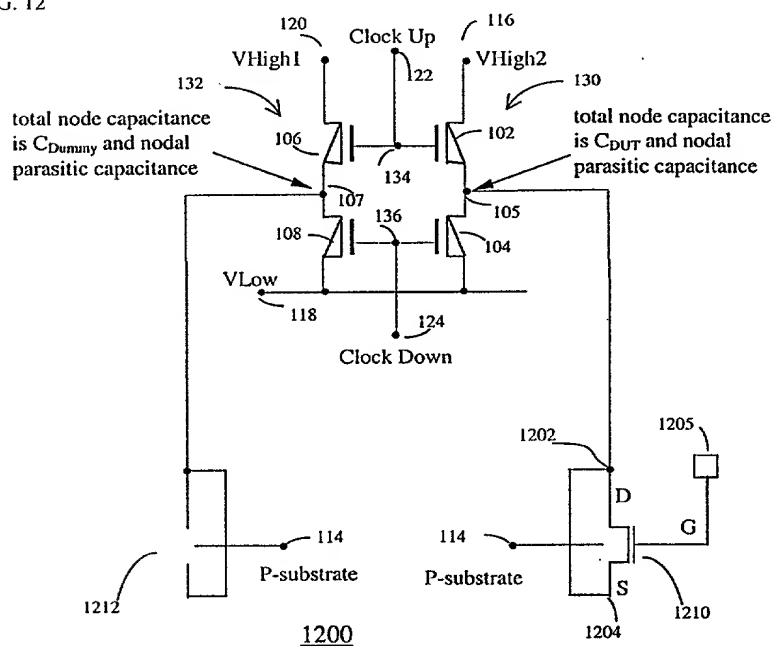
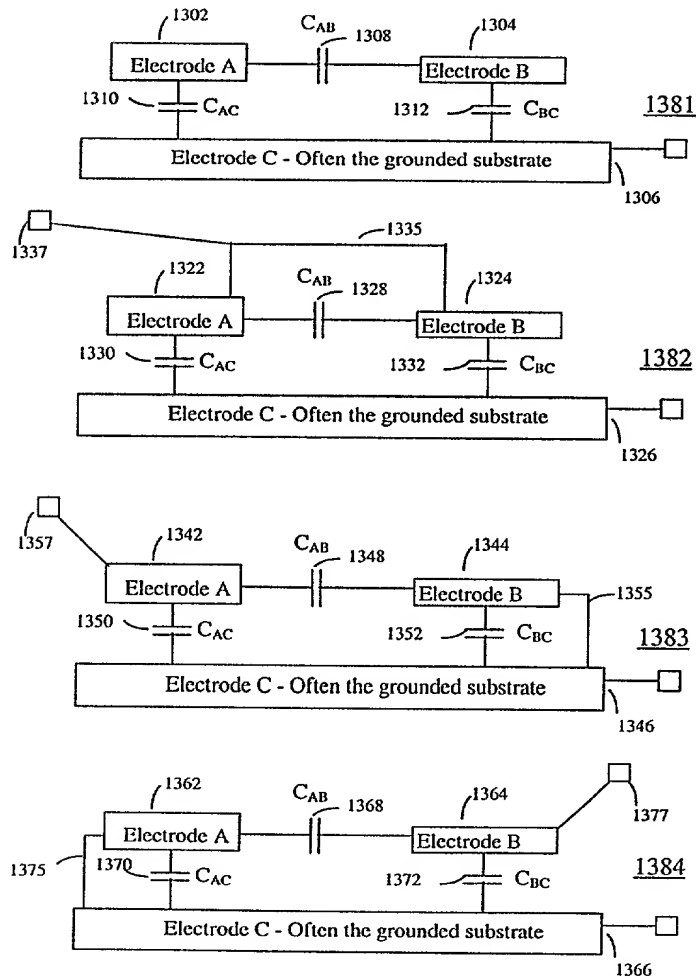


FIG. 12



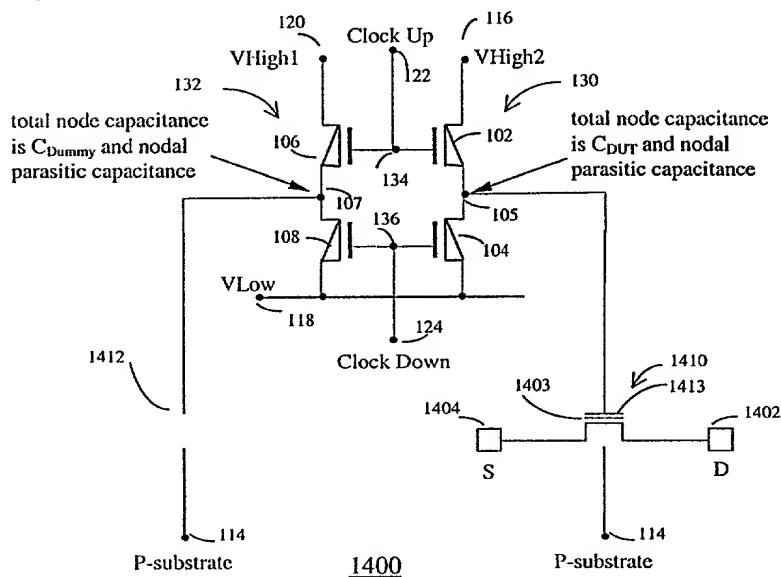
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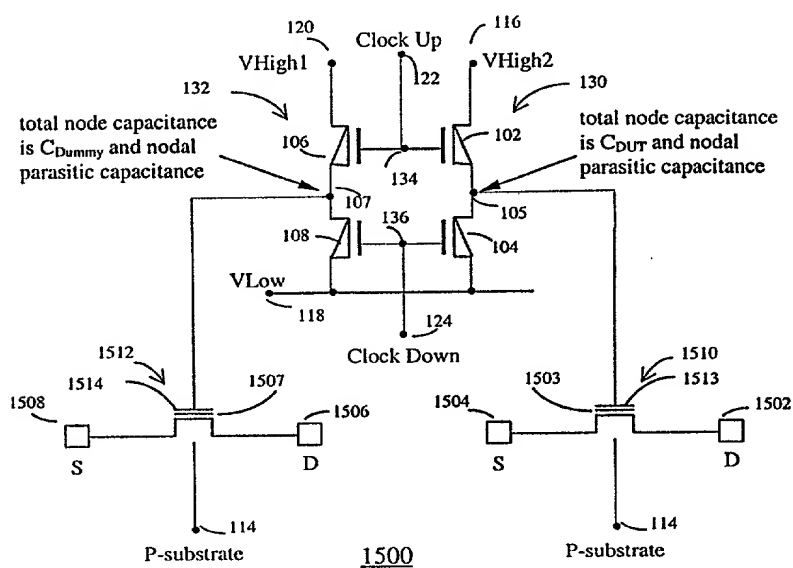
FIG. 13



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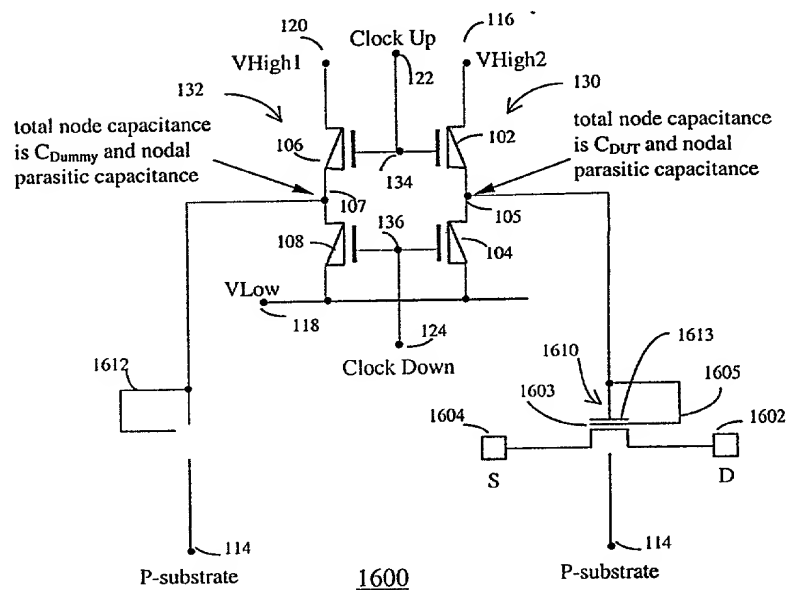
FIG. 14





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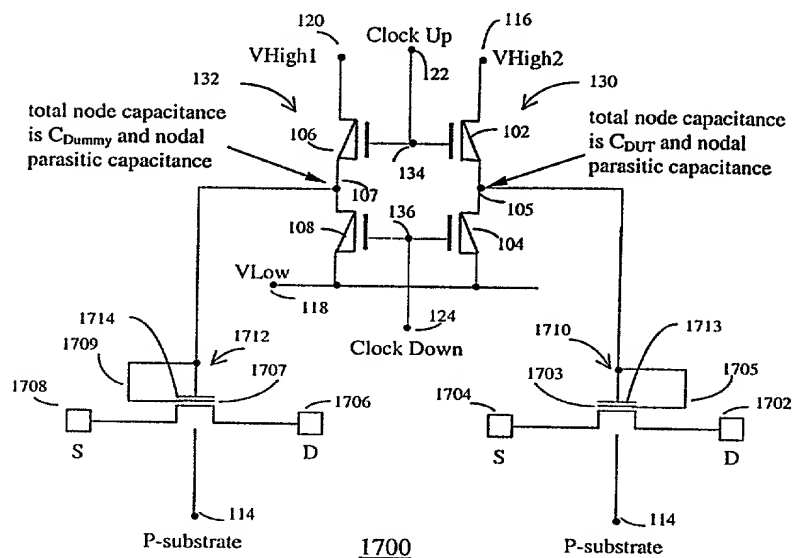
FIG. 16

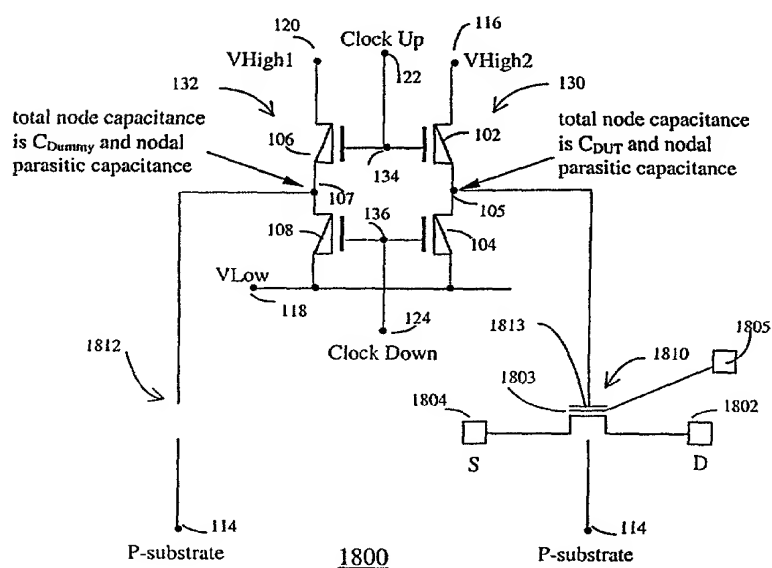




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FIG. 17





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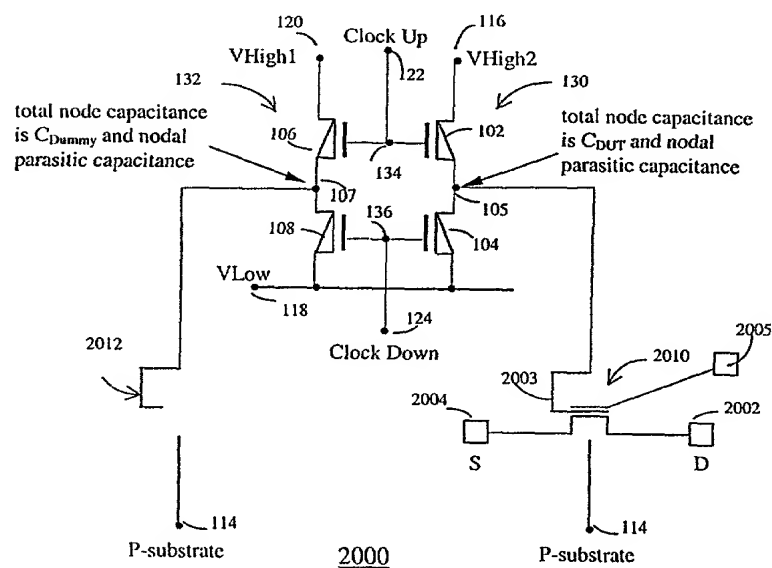
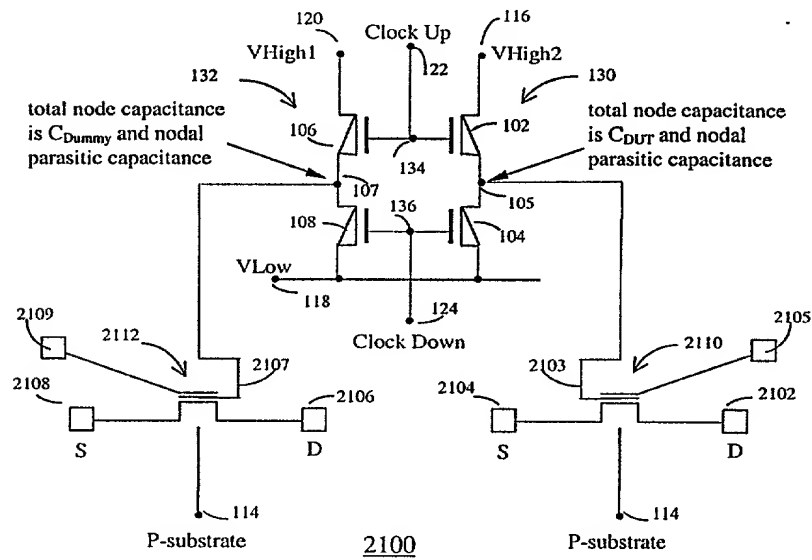
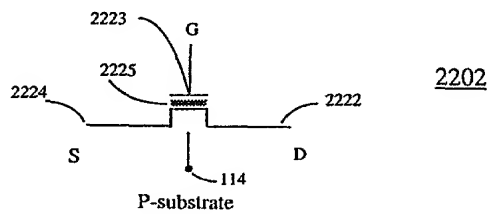
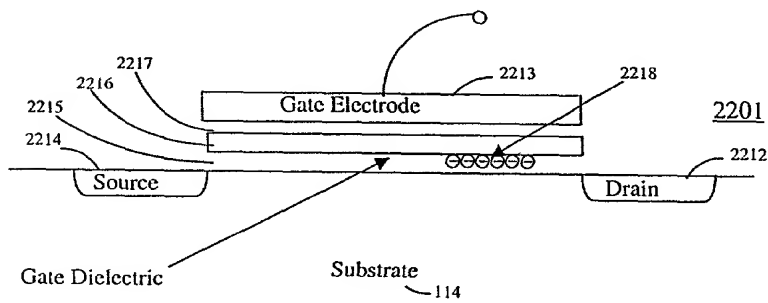
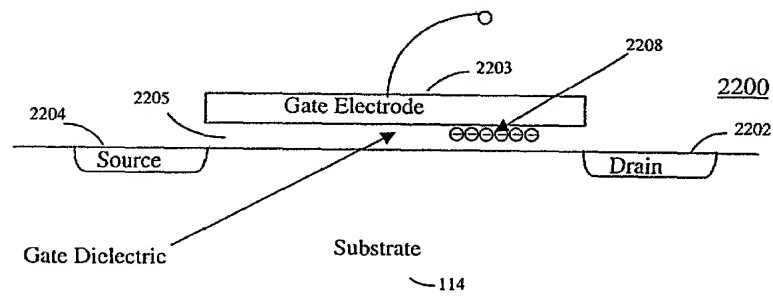


FIG. 21



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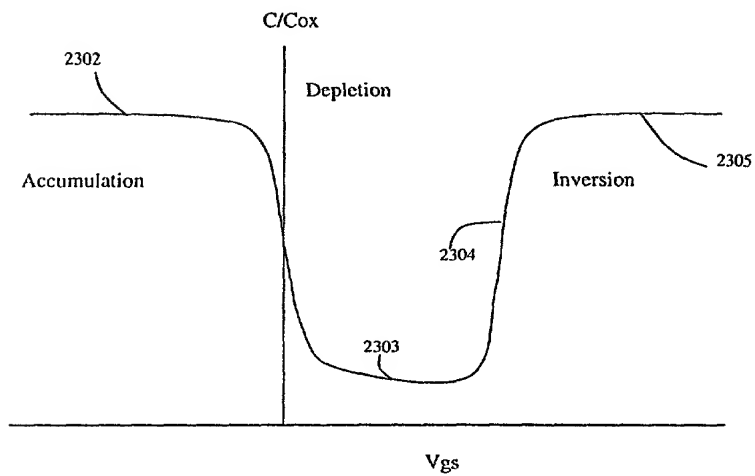
FIG. 22



Patent Application for: CLOCKED BASED METHOD AND DEVICES FOR MEASURING VOLTAGE-VARIABLE  
CAPACITANCES AND OTHER ON-CHIP PARAMETERS  
Inventor(s): David Michael Rogers, et al.  
Attorney Docket No.: 9076/70

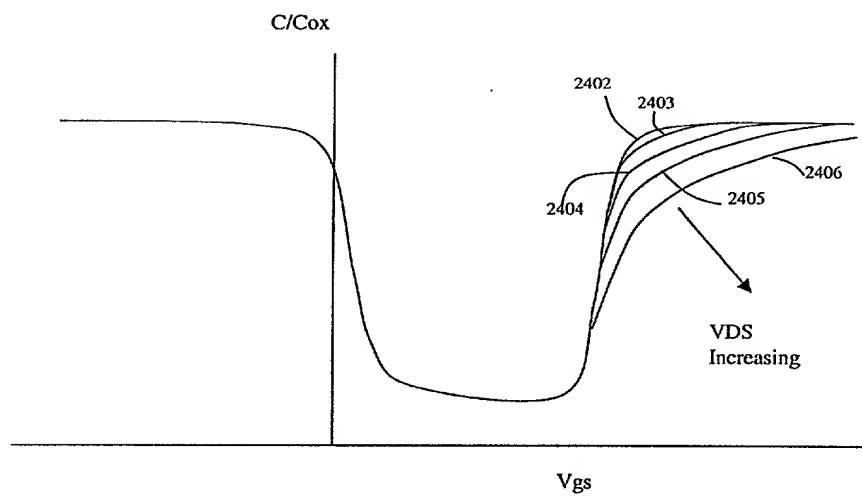
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FIG. 23:



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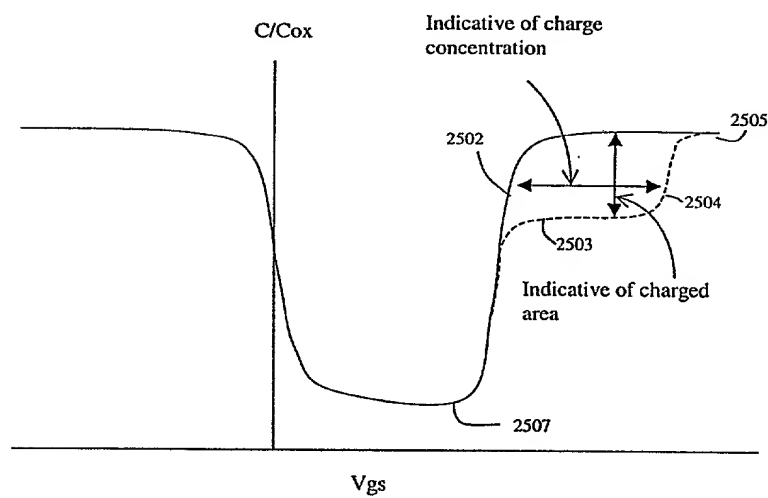
FIG. 24





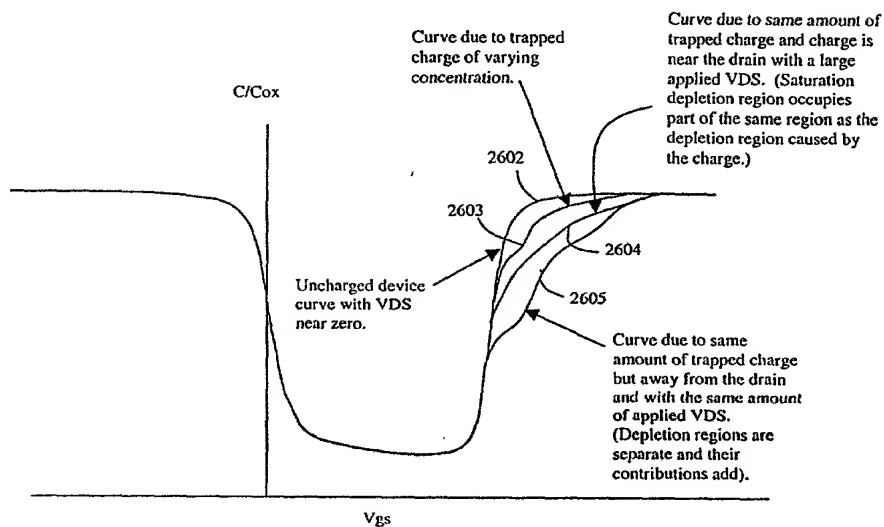
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FIG. 25



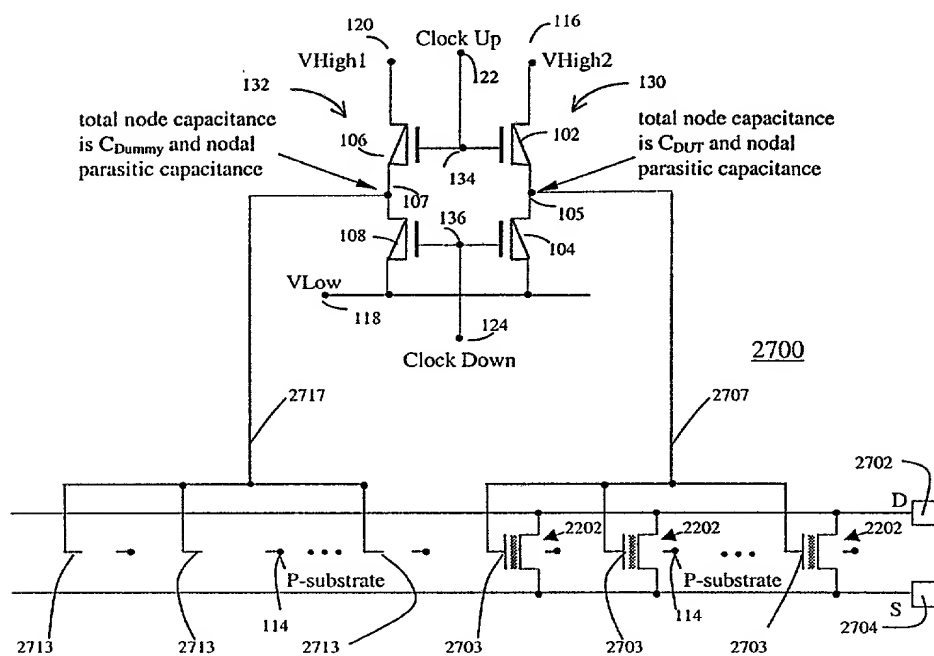
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FIG. 26



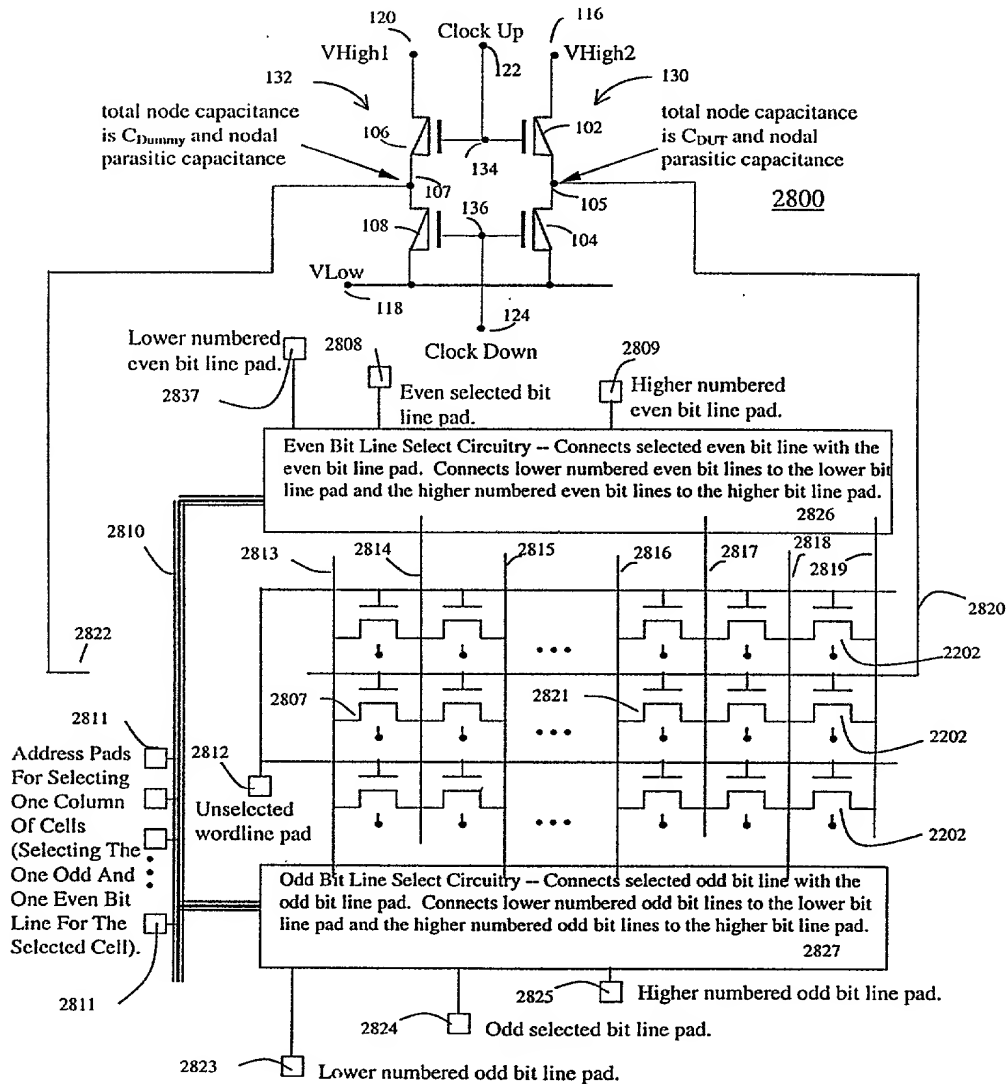
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FIG.27



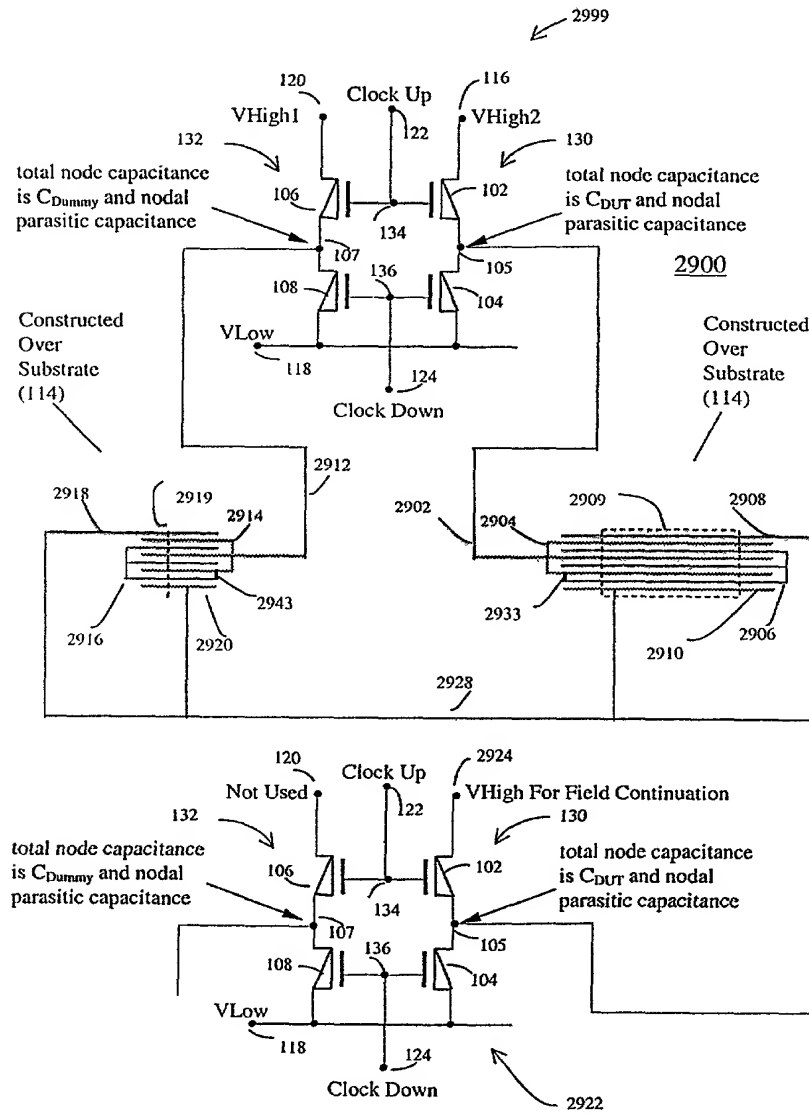
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FIG.28



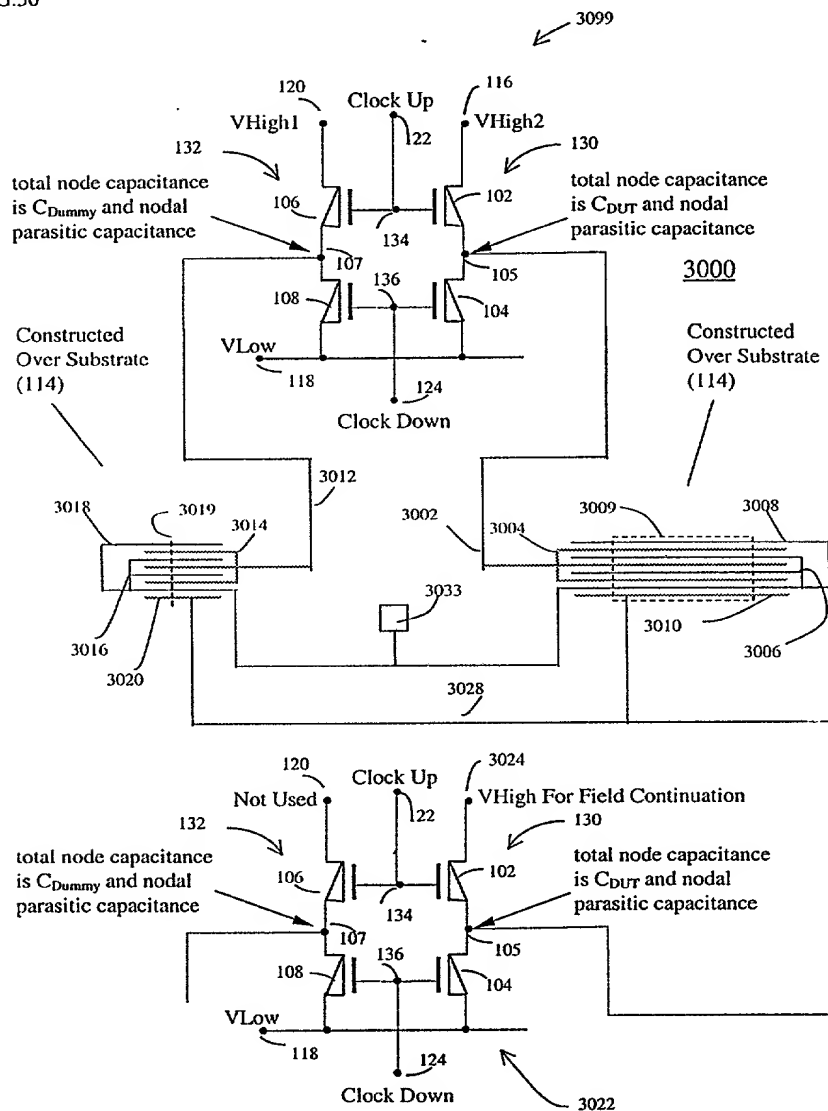
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FIG.29



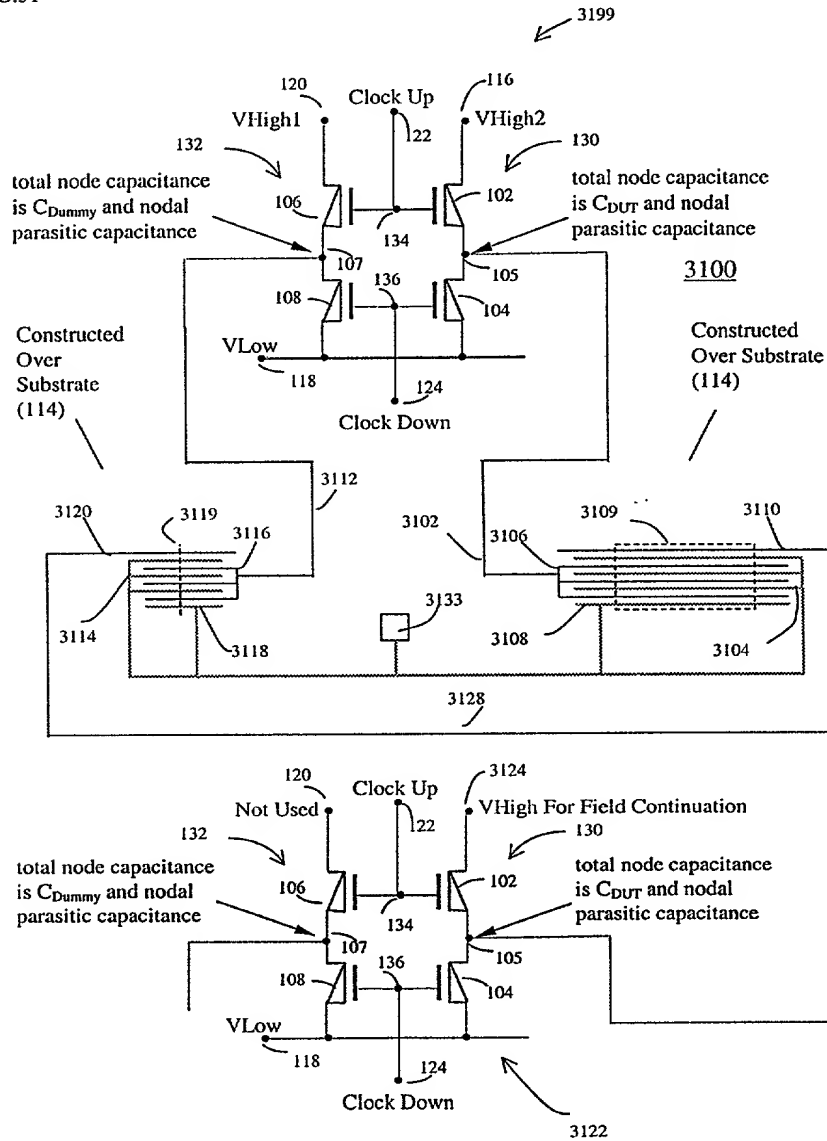
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FIG.30



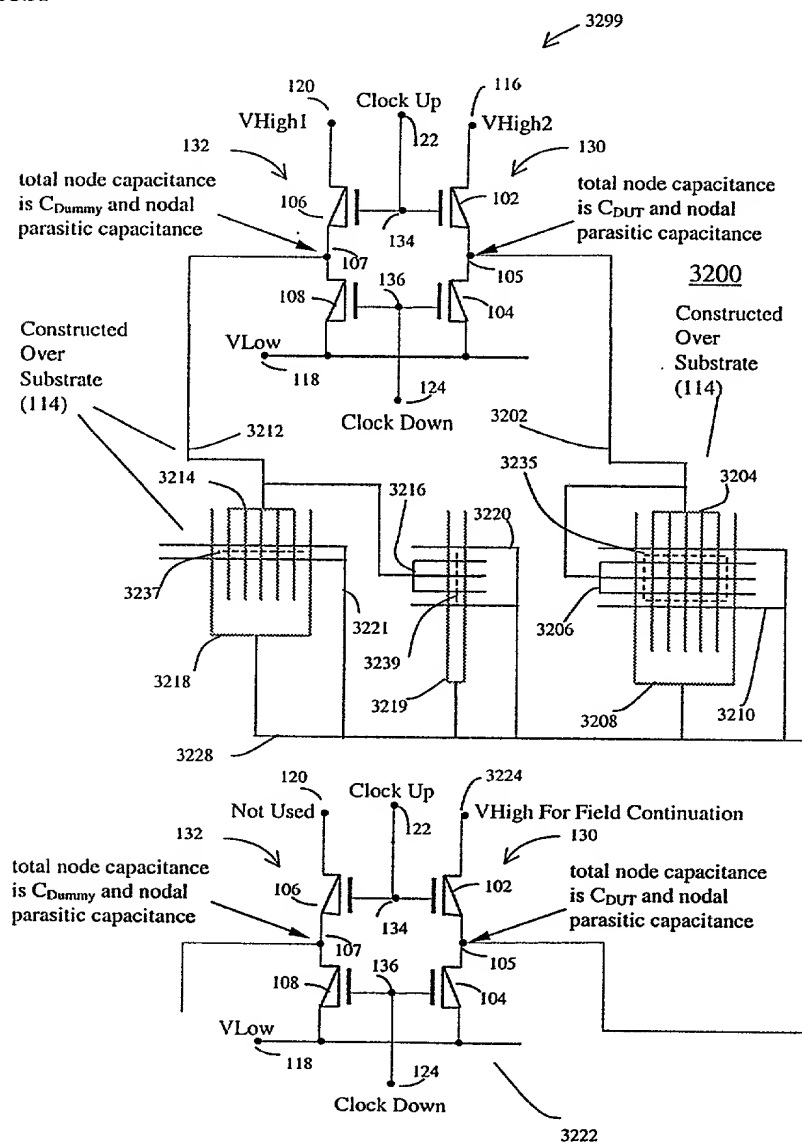
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FIG.31



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FIG.32

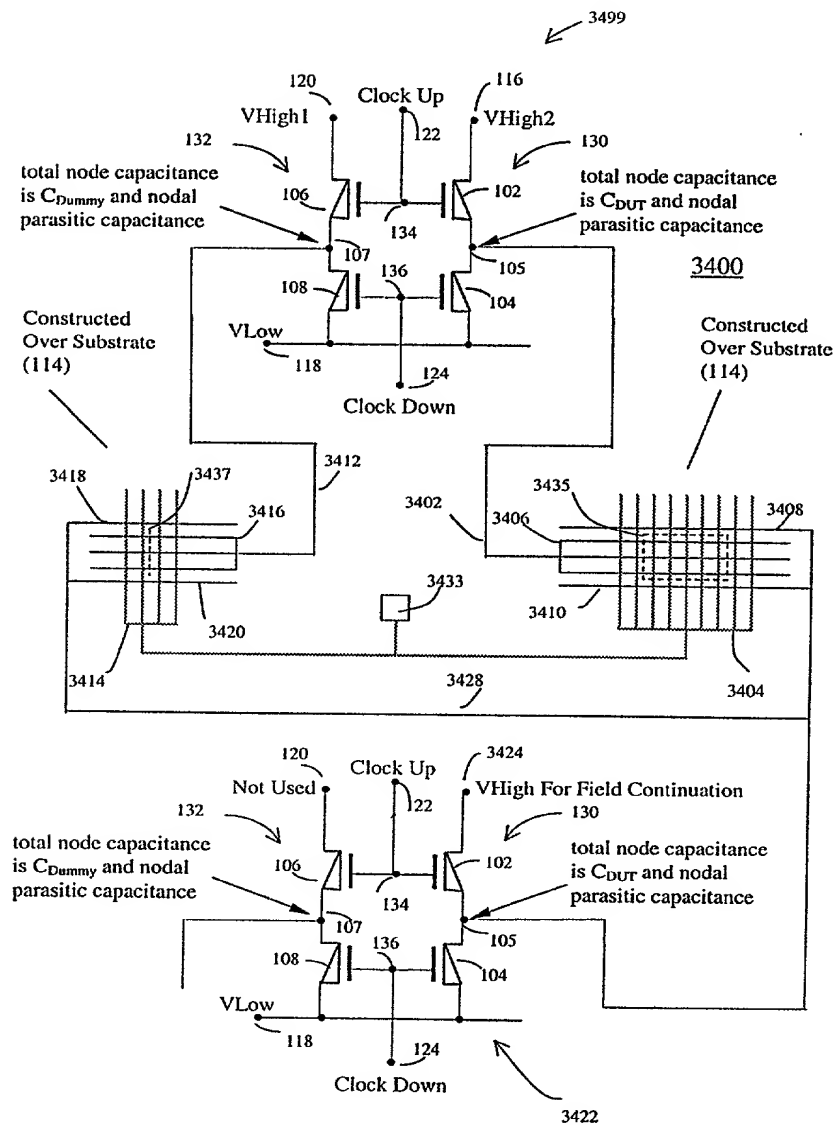






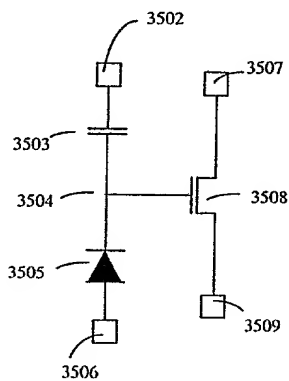
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FIG.34



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FIG. 35



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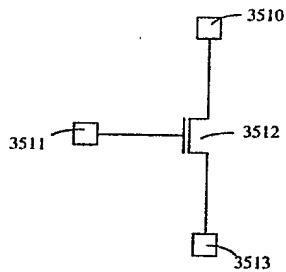
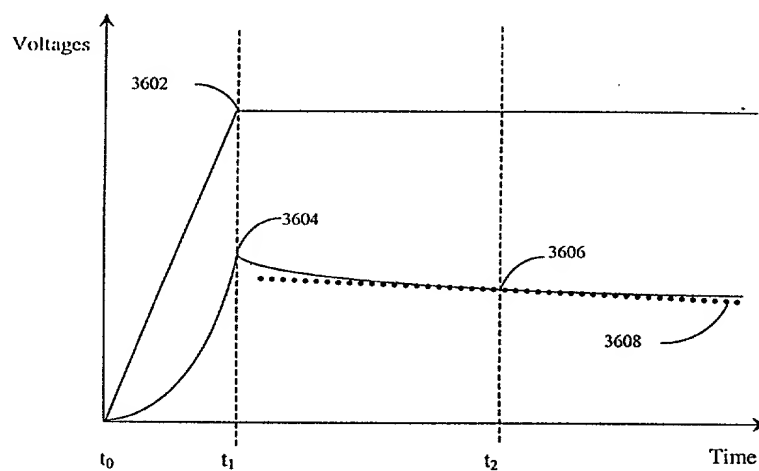


FIG. 36

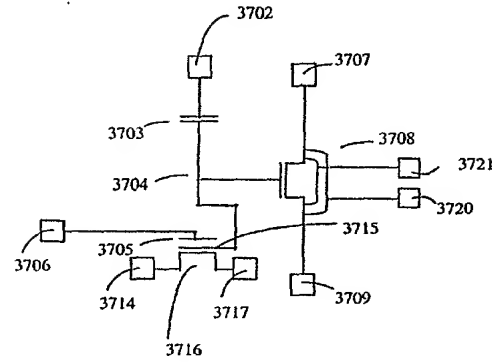
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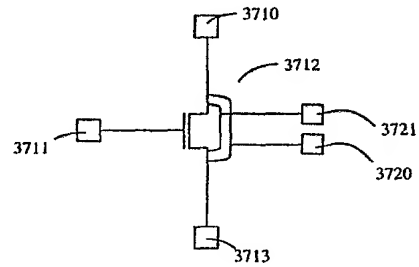
3600

FIG. 37

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[illegible]